



Title of Change:	Qualification of Bucheon 8inch as an additional Wafer FAB facility for Non Punch Through Trench Insulated Gate Bipolar Transistor technology.		
Proposed First Ship date:	28 Aug 2020 or earlier if approved by customer		
Contact Information:	Contact your local ON Semiconductor Sales Office or Sungdae.Shin@onsemi.com		
PCN Samples Contact:	Contact your local ON Semiconductor Sales Office or <PCN.samples@onsemi.com>. Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.		
Type of Notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. An IPCN is an advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change. In case of questions, contact <PCN.Support@onsemi.com>		
Marking of Parts/ Traceability of Change:	Marking is same / trace by date code.		
Change Category:	Wafer Fab Change		
Change Sub-Category(s):	Manufacturing Site Addition		
Sites Affected:			
ON Semiconductor Sites		External Foundry/Subcon Sites	
ON Semiconductor Bucheon, Korea		None	
Description and Purpose:			
Additional qualification of BK 8inch for Non Punch Through Trench Insulated Gate Bipolar Transistor technology for Intelligent Power Module, only qualified wafer size. No change in assembly and test. It is for capacity constrain solution.			
There is no material change and marking change			
Qualification Plan:			
QV DEVICE NAME FNA25060			
RMS: #48681			
PACKAGE: SPM34			
Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj 150°C, Vcc=20V, Vpn= 80% BV	1,008 hrs
HTSL	JESD22-A103	Ta 150°C	1,008 hrs
TC	JESD22-A104	Ta -40°C to +125°C	1,000 cyc
HAST	JESD22-A110	Ta 130°C, RH=85%, Vcc=15V, Vpn= 80% BV	96hrs
UHAST	JESD22-A118	Ta 130°C, RH=85%	96hrs



QV DEVICE NAME FNA23512A

RMS: #49196

PACKAGE: SPM34

Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj 150°C, Vcc=20V, Vpn= 100% BV	1,008 hrs
HTSL	JESD22-A103	Ta 150°C	1,008 hrs
TC	JESD22-A104	Ta -40°C to +125°C	1,000 cyc
HAST	JESD22-A110	Ta 130°C, RH=85%, Vcc=15V, Vpn= 80% BV	96hrs
UHAST	JESD22-A118	Ta 130°C, RH=85%	96hrs

QV DEVICE NAME FSBB10CH120D

RMS: #46522

PACKAGE: SPM3V

Test	Specification	Condition	Interval
HTRB	JESD22-A108	Tj 150°C, Vcc=20V, Vpn= 80% BV	1,008 hrs
HTSL	JESD22-A103	Ta 150°C	1,008 hrs
TC	JESD22-A104	Ta -40°C to +125°C	1,000 cyc
HAST	JESD22-A110	Ta 130°C, RH=85%, Vcc=15V, Vpn= 80% BV	96hrs
UHAST	JESD22-A118	Ta 130°C, RH=85%	96hrs

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

Part Number	Qualification Vehicle
FNA21012A	FNA25060 / FNA23512A / FSBB10CH120D
FNA22512A	FNA25060 / FNA23512A / FSBB10CH120D
FNA23060	FNA25060 / FNA23512A / FSBB10CH120D
FNA23512A	FNA25060 / FNA23512A / FSBB10CH120D
FNA25012A	FNA25060 / FNA23512A / FSBB10CH120D
FNA25060	FNA25060 / FNA23512A / FSBB10CH120D
FNA27560	FNA25060 / FNA23512A / FSBB10CH120D
FSBB10CH120D	FNA25060 / FNA23512A / FSBB10CH120D
FSBB10CH120DF	FNA25060 / FNA23512A / FSBB10CH120D
FSBB10CH120DFL	FNA25060 / FNA23512A / FSBB10CH120D